

APPENDIX 3: Photographs of test setup

Conducted emission

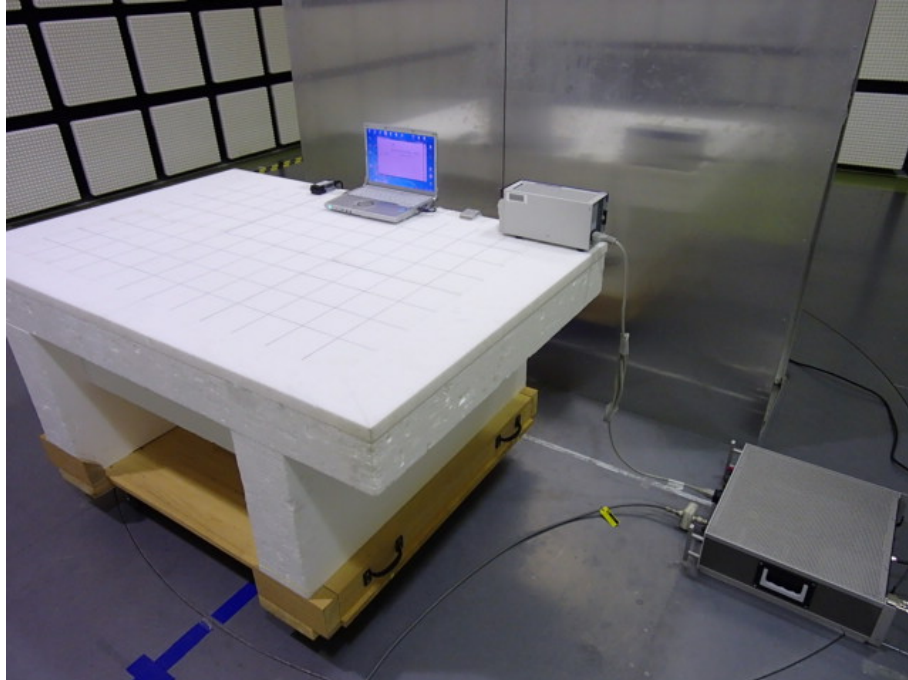


Photo 1

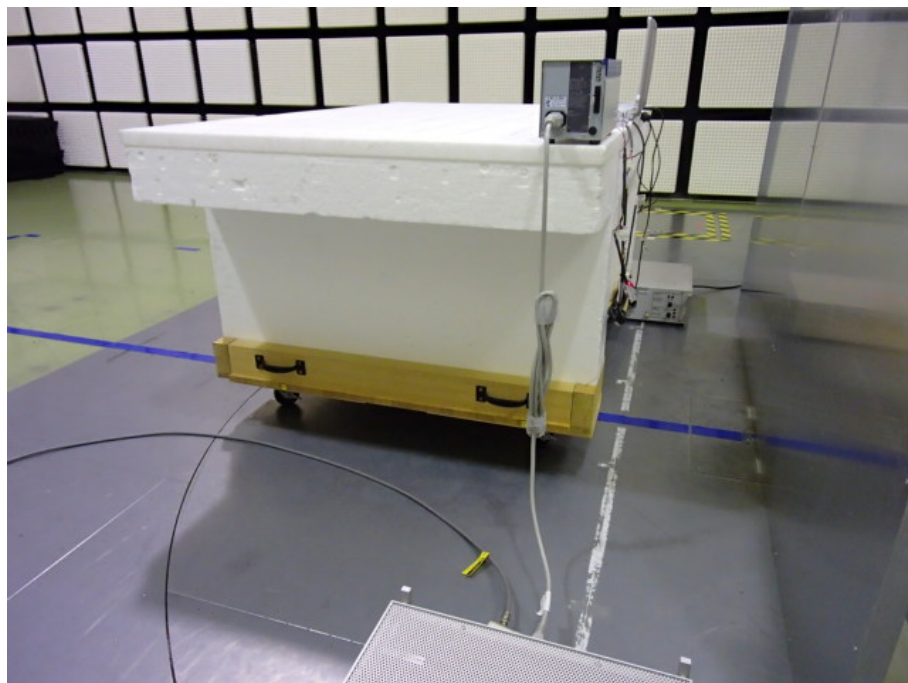


Photo 2

UL Japan, Inc.

Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

Facsimile : +81 596 24 8124

Radiated emission



Photo 1

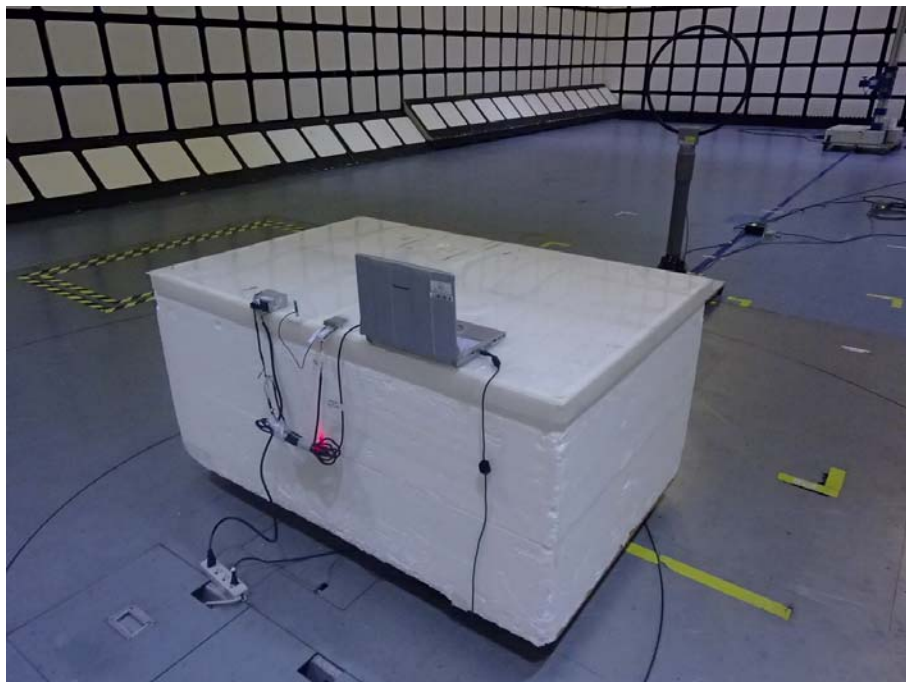


Photo 2

UL Japan, Inc.

Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

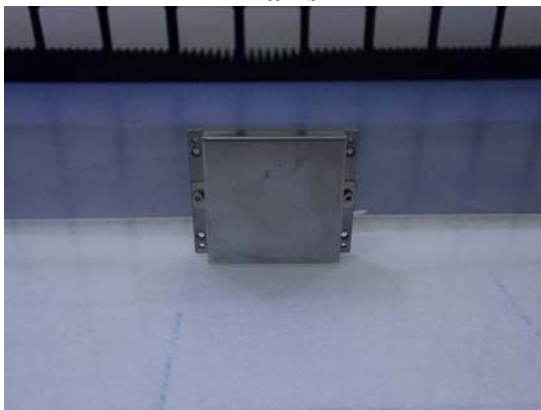
Facsimile : +81 596 24 8124

Worst Case Position

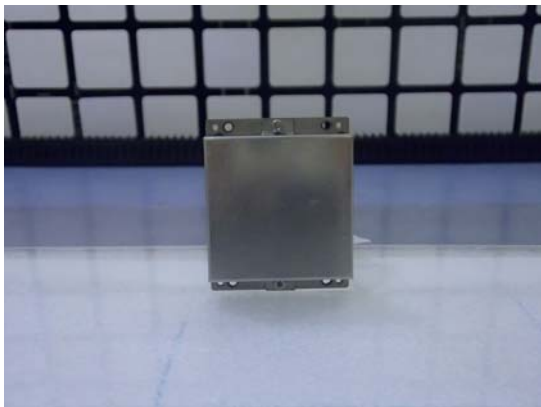
Module
Below 30MHz
X- axis
Above 30MHz
Horizontal: Y-axis / Vertical: Z-axis
X-axis



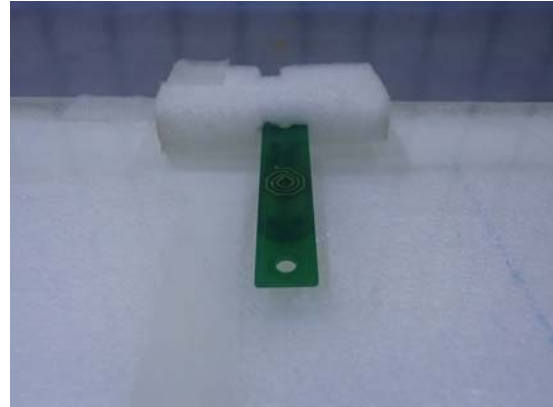
Y-axis



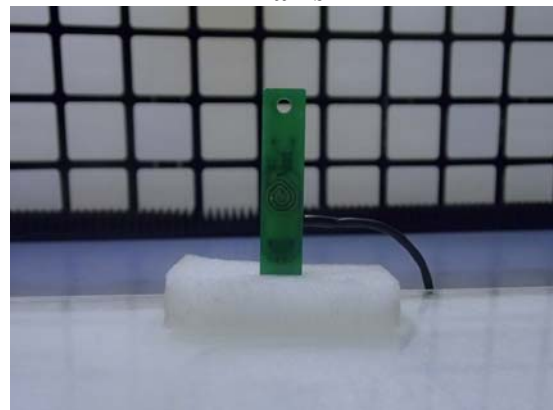
Z-axis



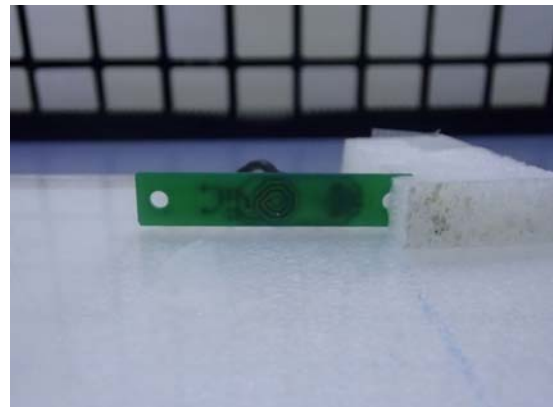
ANT
Below 30MHz
Y-axis
Above 30MHz
Horizontal: Y-axis / Vertical: Z-axis
X-axis



Y-axis

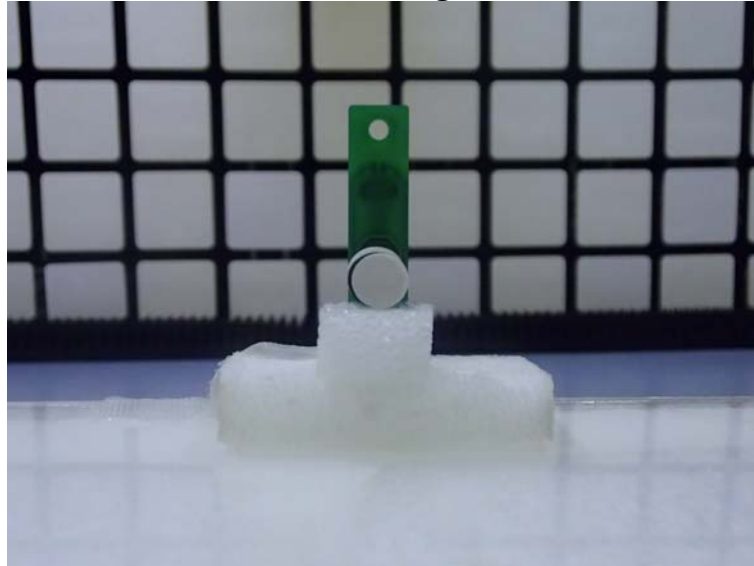


Z-axis

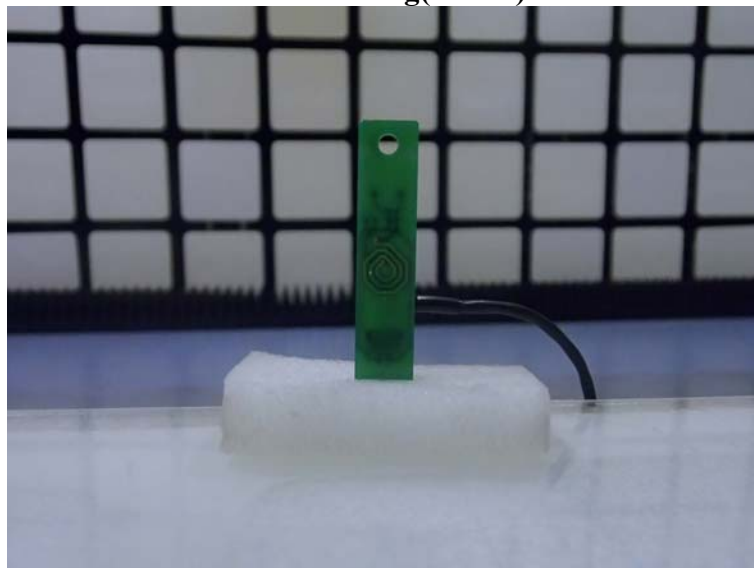


With/Without Tag

With Tag



Without Tag(Worst)



End of Report

UL Japan, Inc.

Ise EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone : +81 596 24 8999

Facsimile : +81 596 24 8124